Form PTO-1449 Sheet 1 of 2

Applicant: Takayuki Mizuno et al. Confirmation No.: 2202
Serial No.: 10/536,649
Att'y Docket No.: 14321.75
Filing Date: May 27, 2005
Art Unit: 2883

For: INTERFERENCE OPTICAL SWITCH AND VARIABLE OPTICAL ATTENUATOR

SUPPLEMENTAL INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANT

		U.S. Patent Documents	1	
Examiner <u>Initial*</u>	Document Number	Issue <u>Date</u>	<u>Name</u>	:
		Foreign Patent Documen	<u>ts</u>	
Examiner <u>Initial</u> *	Document Number	PublicationDate	Country or Patent Office	Translation
1	WO 02/075978 A1	09/26/2002	PCT	N/A
	(i	Other Documents ncluding author, title, pertinent page	ges, etc.)	
Examiner <u>Initial</u> *				
2	Tsutomu Kitoh et al., <i>Novel Broad-Band Optical Switch Using Silica-Based Planar Lightwave Circuit</i> , IEEE Photonics Technology letters, Vol. 4, No. 7, July 1992, pp. 735-737.			
3	Takashi Goh et al., Low Loss and High Extinction Ratio Strictly Nonblocking 16 x Thermooptic Matrix Switch on 6-in Wafer Using Silica-Based Planar Lightwave Circ Technology, Journal of Lightwave Technology, Vol. 19, No. 3, March 2001, pp. 371-379.			ightwave Circuit
Examiner:		Date Considere	ed:	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609, draw line through citation if

not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 Sheet 2 of 2

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References Cited by Applicants

While the filing of Information Disclosure Statements is voluntary, the procedure is governed by the guidelines of Section 609 of the Manual of Patent Examining Procedure and 37 C.F.R. §§ 1.97 and 1.98. To be considered a proper Information Disclosure Statement, Form PTO-1449 shall be accompanied by a copy of each listed patent or publication or other item of information and a translation of the pertinent portions of foreign documents (if an existing translation is readily available to the applicant), an explanation of relevance of each reference not in the English language, and should be submitted in a timely manner as set out in MPEP Sec. 609.

Examiners will consider all citations submitted in conformance with 37 C.F.R. § 1.98 and MPEP Sec. 609 and place their initials adjacent the citations in the spaces provided on this form. Examiners will also initial citations not in conformance with the guidelines which may have been considered. A reference may be considered by the Examiner for any reason whether or not the citation is in full conformance with the guidelines. A line will be drawn through a citation if it is not in conformance with the guidelines AND has not been considered. A copy of the submitted form, as reviewed by the Examiner, will be returned to the applicant with the next communication. The original of the form will be entered into the application file.

Each citation initialed by the Examiner will be printed on the issued patent in the same manner as references cited by the Examiner on Form PTO-892.

The reference designations "A1," "A2," etc. (referring to Applicant's reference 1, Applicant's reference 2, etc.) will be used by the Examiner in the same manner as Examiner's reference designations "A," "B," "C," etc. on Office Action Form PTO-1142.

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Examiner:	Date Considered:

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.